

# Conductivity of metals and semiconductors with defects with long- and short-range potentials in a magnetic field

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The transverse conductivity  $\sigma_{\perp}$  of a metallic system with defects of two types in a classically strong magnetic field  $H$  is examined. The range  $a$  of the potential of one of the defects is much greater than the Larmor radius of an electron  $r$ ; the range of the other defects is shorter than  $r$ . It is shown that the contributions to the conductivity from scattering by different defects are not additive. A dependence of the form  $\sigma_{\perp} \sim H^{-4/3}$  is possible.

The transverse conductivity  $\sigma_{\perp}$  of metals with a closed Fermi surface and of semiconductors in a strong magnetic field  $r \ll l$  ( $l$  is the mean free path of electrons) arises due to the displacement of the centers of electronic orbits as a result of scattering. The conductivity  $\sigma_{\perp}$  is related to the coefficient of diffusion across the magnetic field  $D_{\perp}$  by Einstein's relation, which for a degenerate electron is  $\sigma_{\perp} = e^2(\partial n / \partial \epsilon) D_{\perp}$ , where  $\partial n / \partial \epsilon$  is the state density at the Fermi level. If in each scattering event the center of the orbit of an electron is displaced in a random manner, then the diffusion coefficient is (see Ref. 1, p. 457)

$$D_{\perp} = \frac{\sum (\Delta x)^2}{2\delta t}, \quad (1)$$

where the summation extends over collisions experienced by an electron in a time

interval  $\delta t$ , and  $\Delta x$  is the change in the  $x$  coordinate of the center of the orbit as a result of the collision.

Relation (1) is valid for scattering by phonons<sup>2</sup> or point defects.<sup>3</sup> However, as will be shown below, it is not always valid in a system with randomly distributed defects, whose potential range satisfies the inequality  $r \ll a \ll l$ . This condition can be satisfied, for example, for the potential of dislocations in a crystal or the potential of ionized impurities in semiconductors.

In this paper we examine the conductivity of a degenerate electron gas in a crystal with defects of two types. The range of the potential of one of the defects is  $a \ll r$ , and that of the other is  $b \ll r$ . We shall assume that the long-range potential is smooth and that it has an amplitude  $u_0 \ll \epsilon_F$ , where  $\epsilon_F$  is the Fermi energy of electrons. The density of defects with this potential is  $n \lesssim a^{-3}$ . For scattering by short-range defects we introduce the momentum relaxation time  $\tau$ . In the absence of long-range defects the coefficient of diffusion across the magnetic field would be  $D_{\perp} \sim r^2/\tau$ , while for diffusion along the field it would be  $D_{\parallel} \sim v_F^2 \tau$ , where  $v_F$  is the Fermi velocity. In contrast to Refs. 4 and 5, we examine the case in which  $l = v_F \tau \gg a$ ,  $(na^2)^{-1}$ . Here  $(na^2)^{-1}$  is the mean free path of electrons between collisions with the long-range defects. The relaxation of the longitudinal component of the momentum by defects  $a$  can be ignored, since  $n_0 \ll \epsilon_F$ . Scattering by defects  $a$  can be viewed as a drift in crossed fields: The field  $H$  and the field of the defect,  $E \sim u_0/ea$  (see Ref. 1, p. 308). A single scattering event  $a$  displaces the center of the orbit of an electron by an amount  $\Delta x \sim v_{dr} \Delta t \sim n(u_0/\epsilon_F)$ , where  $v_{dr} \sim c(u_0/eHa)$  is the drift velocity, and  $\Delta t \sim a/v_F$  is the transit time of the electron in the field of the defect. The transverse displacement of the electron along its mean free path in the direction of the magnetic field  $l$ , due to the interaction with defects  $a$ , is  $\Delta x_l \sim r(u_0/\epsilon_F)(na^2 l)^{1/2} \sim n(u_0/\epsilon_F)(\tau/\tau_0)^{1/2}$ , where  $\tau_0 = (na^2 v_F)^{-1}$ . It is assumed that  $\Delta x_l \ll a$ .

The main feature of our analysis is that the electron, after being scattered once by a defect of size  $a$  will return during the random motion along the magnetic field many times to the defect before it is displaced across the field by a distance  $\simeq a$ . Moving in the field of the long-range defect under examination, the electron will be displaced each time approximately in the same direction by an amount  $\simeq \Delta x$ . The total displacement is  $\simeq \Delta x M$  ( $M$  is the number of times the electron returns to the defect), whereas Eq. (1) yields a displacement  $\simeq \Delta x M^{1/2}$  due to these distance collisions. The transverse motion of the electron by a distance shorter than  $a$  has a nondiffusive nature and becomes diffusive only a scale greater than  $a$ . The step of such diffusion is on the order of  $a$ , and the diffusion coefficient is  $D_{\perp} \sim a^2/t_0$  where  $t_0$  is the time over which the electron is displaced by a distance  $\sim a$ . To determine  $t_0$  we must find the displacement of the electron  $\Delta X(t)$  as a function of time for  $\Delta X(t)$  smaller than  $a$ . We can find  $t_0$  from the equation  $\Delta X(t) \simeq a$ .

To find  $\Delta X(t)$  we will make use of the fact that the probability for observing an electron a second time in the field of the defect under examination after a time  $t$  is  $a/(D_{\parallel} t)^{1/2}$ . The average drift velocity under the action of only a single defect is  $v_{dr} \sim v_{dr} a/(D_{\parallel} t)^{1/2}$ . The corresponding displacement is  $\Delta x_1(t) \sim v_{dr} a/(t/D_{\parallel})^{1/2} \sim v_F(u_0/\epsilon_F)(t/D_{\parallel})$ . The number of long-range defects with which the electron interacts within a time  $t$  is on the order of  $(D_{\parallel} t)^{1/2}/(na^2)^{-1}$ . Because of the random distribution of defects, the square of the displacement of an electron over a time  $t$  as a

result of interaction with all defects, both long- and short-range, is

$$[\overline{\Delta X(t)}]^2 \sim [\Delta x_{\parallel}(t)]^2 \frac{(D_{\parallel} t)^{1/2}}{(na^2)^{-1}} + \frac{r^2}{\tau} t \sim \left( r v_F \frac{u_0}{\epsilon_F} \right)^2 t^{3/2} D_{\parallel}^{-1/2} na^2 + r^2 \frac{t}{\tau}. \quad (2)$$

The time  $t_0$  can be found from the approximate equality  $[\overline{\Delta X(t)}]^2 \approx a$ . The diffusion coefficient is

$$D_{\perp} \sim \frac{a^2}{t_0} \sim \left( r v_F \frac{u_0}{\epsilon_F} \right)^2 (t_0/D_{\parallel})^{1/2} na^2 + r^2/\tau. \quad (3)$$

If the first term in (3) is much larger than the second term, we would have

$$D_{\perp} = D_1 \sim (r^4 a^2 / \tau \tau_0^2)^{1/3} (u_0 / \epsilon_F)^{4/3} \propto H^{-4/3}. \quad (4)$$

We see that the contribution of scattering by long-range and short-range defects to the diffusion coefficient [and therefore to the conductivity  $\sigma_{\perp} = e^2(\partial n / \partial \epsilon) D_{\perp}$ ] is not additive. The quantity  $D_1 > r^2/\tau$ , if  $(a/r)(\tau/\tau_0)(u_0/\epsilon_F)^2 > 1$ .

We ignored the displacement of electrons in states in which the energy of motion along the magnetic field is  $\epsilon_z < u_0$ . In the case of a repulsive potential  $u_0$  an electron with  $\epsilon_z < u_0$  is trapped for some time between two neighboring long-range defects, reflecting first from one defect and then from the other [under the condition that  $\tau > \tau_0(\epsilon_F/\epsilon_z)^{1/2}$ ]. The motion across the magnetic field is on the average driftlike. Under certain conditions the transverse diffusion is determined by the motion of electrons in states with  $\epsilon_z < u_0$ . Taking this into account leads to an additional restriction for expression (4),  $(r/a) < (\epsilon_F/u_0)^{7/4}(\tau_0/\tau)^2$ .

The mechanism for transverse diffusion of electrons which we examined above could conceivably account for the deviation from the law  $\sigma_{\perp} \propto H^{-2}$  in bismuth, observed in magnetic fields stronger than 1 kOe (see, for example, Ref. 6). The characteristic scale of the dislocation field nonuniformity is  $a \sim N^{-1/2}$ , where  $N$  is the number of dislocations threading through a cross section of unit area. For  $N \sim 10^6 \text{ cm}^{-2}$  we have  $a \sim 10^{-3} \text{ cm}$ . The time is  $\tau_0 \sim (N a v_F)^{-1} \sim a/v_F$ . In a magnetic field we have  $H = 10 \text{ kOe}$ , in which the deviation from the law  $\sigma_{\perp} \propto H^{-2}$ , observed in Ref. 6, reaches 100%,  $r \simeq 10^{-5} \text{ cm}$ . Setting  $u_0 \sim \Lambda(b/a) \sim 10^{-4} \text{ eV}$ , where  $b \simeq 10^{-7} \text{ cm}$  is the modulus of Burgers' vector,  $\Lambda \simeq 1 \text{ eV}$  is the strain potential,  $\epsilon_F \simeq 10^{-2} \text{ eV}$ , and  $l \simeq 10^{-2} \text{ cm}$ , we find that  $(\tau/\tau_0)(u_0/\epsilon_F) \sim 10^{-2} \sim r/a$ . This is the condition for which  $D_1$  is comparable to  $r^2/\tau$ . In stronger fields  $D_1 \propto H^{-4/3}$  dominates.

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